Application/Control No. Applicant(s)/Patent Under Reexamination 10/751,436 LEE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 CongVan Tran 2617 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-2002/0186679 12-2002 Α Nakatsugawa et al. 370/349 US-В US-С US-D US-Ε US-F US-G US-Н US-US-J US- . Κ US-L US-FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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